Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/710,414	BILAK ET AL.
Examiner	Art Unit
Alan S. Chen	2182

SEARCHED					
Class	Subclass	Date	Examiner		
710	22	5/26/2006	ASC		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	5/26/3006	ASC		